CY54/74FCT2827T
10-BIT BUFFER

FEATURES

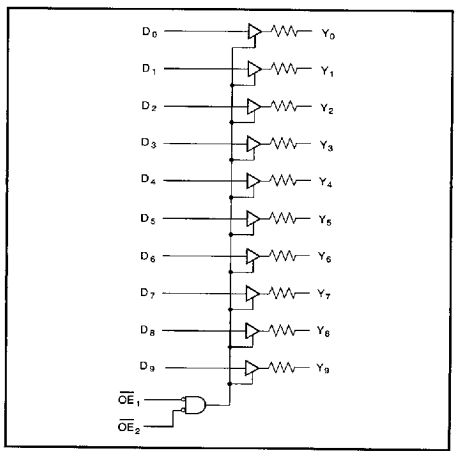
- **Function and Drive Compatible with the FCT, F and AM29827 Logic**
- **FCT-B speed at 5.0ns max. (Commercial) FCT-A speed at 8.0ns max. (Commercial)**
- **R25Ω output series resistors to reduce transmission line reflection noise**
- **Reduced V_{OH} (typically = 3.3V) versions of Equivalent FCT functions**
- **Edge-rate Control Circuitry for Significantly Improved Noise Characteristics**
- **Power-off disable feature**
- **Matched Rise and Fall times**
- **Fully Compatible with TTL Input and Output Logic Levels**
- **12 mA Sink Current (Com'l), 12 mA (Mil) 15 mA Source Current (Com'l), 12 mA (Mil)**

DESCRIPTION

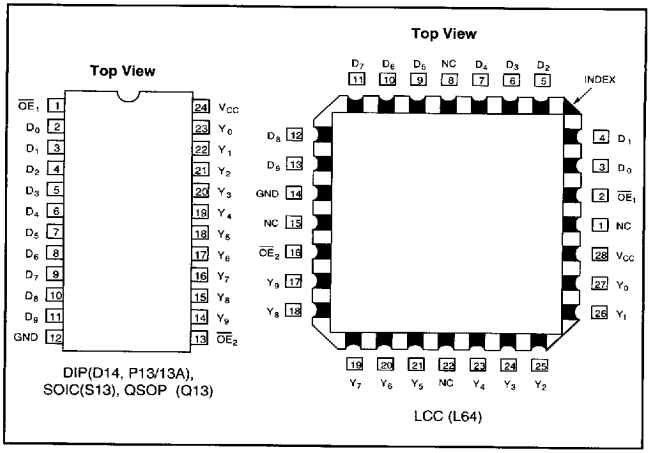
The 'FCT2827T 10-bit bus driver provides high-performance bus interface buffering for wide data/address paths or buses carrying parity. This 10-bit buffer has NOR-ed output enables for maximum control flexibility. The non-inverting 'FCT2827T is designed for high-capacitance load drive capability, while providing low-capacitance bus loading at both inputs and outputs. All inputs have clamp diodes and all outputs are designed for low-capacitance bus loading in the high-impedance state. On-chip termination resistors have been added to the outputs to reduce system noise caused by reflections. The 'FCT2827T can be used to replace the 'FCT827T to reduce noise in an existing design.

3

LOGIC BLOCK DIAGRAM



PIN CONFIGURATIONS



ABSOLUTE MAXIMUM RATINGS[1,2]

Symbol	Parameter	Value	Unit
T_{STG}	Storage Temperature	–65 to +150	°C
T_A	Ambient Temperature Under Bias	–65 to +135	°C
V_{CC}	V_{CC} Potential to Ground	–0.5 to +7.0	V
P_T	Power Dissipation	0.5	W
I_{OUTPUT}	Current Applied to Output	120	mA
V_{IN}	Input Voltage	–0.5 to +7.0	V
V_{OUT}	Voltage Applied to Output	–0.5 to +7.0	V

RECOMMENDED OPERATING CONDITIONS

Free Air Ambient Temperature	Min	Max
Military	–55°C	+125°C
Commercial	0°C	+70°C

Supply Voltage (V_{CC})	Min	Max
Military	+4.5V	+5.5V
Commercial	+4.75V	+5.25V

DC ELECTRICAL CHARACTERISTICS (Over recommended operating conditions)

Symbol	Parameter		Min	Typ[3]	Max	Units	V_{CC}	Conditions
V_{IH}	Input HIGH Voltage		2.0			V		
V_{IL}	Input LOW Voltage				0.8	V		
V_H	Hysteresis			0.2		V		All inputs
V_{IK}	Input Clamp Diode Voltage			–0.7	–1.2	V	MIN	I_{IN} = –18mA
V_{OH}	Output HIGH Voltage	Military	2.4	3.3		V	MIN	I_{OH} = –12mA
		Commercial	2.4	3.3		V	MIN	I_{OH} = –15mA
V_{OL}	Output LOW Voltage	Military		0.3	0.5	V	MIN	I_{OL} = 12mA
		Commercial		0.3	0.5	V	MIN	I_{OL} = 12mA
R_{OUT}	Output Resistance	Military		25		Ω	MIN	I_{OL} = 12mA
		Commercial	20	25	40	Ω	MIN	I_{OL} = 12mA
I_I	Input HIGH Current				20	µA	MAX	$V_{IN} = V_{CC}$
I_{IH}	Input HIGH Current				5	µA	MAX	V_{IN} = 2.7V
I_{IL}	Input LOW Current				–5	µA	MAX	V_{IN} = 0.5V
I_{OZH}	Off State I_{OUT} HIGH-Level Output Current				10	µA	MAX	V_{OUT} = 2.7V
I_{OZL}	Off State I_{OUT} LOW-Level Output Current				–10	µA	MAX	V_{OUT} = 0.5V
I_{OS}	Output Short Circuit Current[4]		–60	–120	–225	mA	MAX	V_{OUT} = 0.0V
I_{OFF}	Power-off Disable				100	µA	0V	V_{OUT} = 4.5V
C_{IN}	Input Capacitance[5]			6	10	pF	MAX	All inputs
C_{OUT}	Output Capacitance[5]			8	12	pF	MAX	All outputs
I_{CC}	Quiescent Power Supply Current			0.2	1.5	mA	MAX	$V_{IN} \leq 0.2V$, $V_{IN} \geq V_{CC}-0.2V$

Notes:

1. Operation beyond the values set forth in the above table may impair the useful life of the device. Unless otherwise noted, these values are over the operating free-air temperature range.
2. Unused inputs must always be connected to an appropriate logic voltage level, preferably either V_{CC} or ground
3. Typical values are at V_{CC} = 5.0V, T_A = +25°C ambient
4. Not more than one output should be shorted at a time. Duration of short should not exceed one second. The use of high speed test apparatus and/or sample and hold techniques are preferable in order to minimize internal chip heating and more accurately reflect operational values. Otherwise prolonged shorting of a high output may raise the chip temperature well above normal and thereby cause invalid readings in other parameter tests. In any sequence of parameter tests, I_{OS} tests should be performed last.
5. This parameter is guaranteed but not tested.

DC CHARACTERISTICS (Over recommended operating conditions unless otherwise specified.)

Symbol	Parameter	Typ[3]	Max	Units	Conditions
ΔI_{CC}	Quiescent Power Supply Current (TTL inputs)	0.5	2.0	mA	V_{CC} = MAX, V_{IN} = 3.4V[6], f_1 = 0, Outputs Open
I_{CCD}	Dynamic Power Supply Current[7]	0.15	0.25	mA/ MHz	V_{CC} = MAX, One Input Toggling, 50% Duty Cycle, Outputs Open, $\overline{OE}_1$ = $\overline{OE}_2$ = GND, $V_{IN} \leq 0.2V$ or $V_{IN} \geq V_{CC} - 0.2V$
I_C	Total Power Supply Current[9]	1.7	4.0	mA	V_{CC} = MAX, 50% Duty Cycle, Outputs Open, One Bit Toggling at f_1 = 10MHz, $\overline{OE}_1$ = $\overline{OE}_2$ = GND, $V_{IN} \leq 0.2V$ or $V_{IN} \geq V_{CC} - 0.2V$
		2.0	5.0	mA	V_{CC} = MAX, 50% Duty Cycle, Outputs Open, One Bit Toggling at f_1 = 10MHz, $\overline{OE}_1$ = $\overline{OE}_2$ = GND, V_{IN} = 3.4V or V_{IN} = GND
		3.2	6.5[8]	mA	V_{CC} = MAX, 50% Duty Cycle, Outputs Open, Eight Bits Toggling at f_1 = 2.5MHz, $\overline{OE}_1$ = $\overline{OE}_2$ = GND, $V_{IN} \leq 0.2V$ or $V_{IN} \geq V_{CC} - 0.2V$
		5.2	14.5[8]	mA	V_{CC} = MAX, 50% Duty Cycle, Outputs Open, Eight Bits Toggling at f_1 = 2.5MHz, $\overline{OE}_1$ = $\overline{OE}_2$ = GND, V_{IN} = 3.4V or V_{IN} = GND

Notes:

6. Per TTL driven input (V_{IN} = 3.4V); all other inputs at V_{CC} or GND.
7. This parameter is not directly testable, but is derived for use in Total Power Supply calculations.
8. Values for these conditions are examples of the I_{CC} formula. These values are guaranteed but not tested.
9. $I_C = I_{QUIESCENT} + I_{INPUTS} + I_{DYNAMIC}$
   $I_C = I_{CC} + \Delta I_{CC} D_H N_T + I_{CCD}(f_0/2 + f_1 N_1)$
   I_{CC} = Quiescent Current with CMOS input levels
   ΔI_{CC} = Power Supply Current for a TTL High Input (V_{IN} = 3.4V)
   D_H = Duty Cycle for TTL Inputs High
   N_T = Number of TTL Inputs at D_H
   I_{CCD} = Dynamic Current Caused by an Input Transition Pair (HLH or LHL)
   f_0 = Clock Frequency for Register Devices (Zero for Non-Register Devices)
   f_1 = Input Frequency
   N_1 = Number of Inputs at f_1

All currents are in milliamps and all frequencies are in megahertz.

FUNCTION TABLES

'FCT2827T (Non-Inverting)

Inputs			Outputs	Function
$\overline{OE}_1$	$\overline{OE}_2$	D_i	Y_i	
L	L	L	L	Transparent
L	L	H	H	
H	X	X	Z	Three-State
X	H	X	Z	

Note:
H = High, L = Low, X = Don't Care, Z = High Impedance

AC CHARACTERISTICS

Sym.	Parameter	Test Conditions	'FCT2827AT				'FCT2827BT				Units	Fig. No.*
			MIL		COM'L		MIL		COM'L			
			Min.[10]	Max.	Min.[10]	Max.	Min.[10]	Max.	Min.[10]	Max.		
t_{PLH} t_{PHL}	Propagation Delay from D_1 to Y_1	C_L = 50pF R_L = 500Ω	–	9.0	–	8.0	–	6.5	–	5.0	ns	1,3
t_{PLH} t_{PHL}	Propagation Delay from D_1 to Y_1	C_L = 300pF[11] R_L = 500Ω	–	17.0	–	15.0	–	14.0	–	13.0	ns	1,3
t_{PZH} t_{PZL}	Output Enable Time $\overline{OE}$ to Y_1	C_L = 50pF R_L = 500Ω	–	13.0	–	12.0	–	9.0	–	8.0	ns	1,2
t_{PZH} t_{PZL}	Output Enable Time $\overline{OE}$ to Y_1	C_L = 300pF[11] R_L = 500Ω	–	25.0	–	23.0	–	16.0	–	15.0	ns	1,2
t_{PHZ} t_{PHL}	Output Disable Time $\overline{OE}$ to Y_1	C_L = 5pF[11] R_L = 500Ω	–	10.0	–	9.0	–	7.0	–	6.0	ns	1,7,8
t_{PHZ} t_{PHL}	Output Disable Time $\overline{OE}$ to Y_1	C_L = 50pF[11] R_L = 500Ω	–	10.0	–	9.0	–	8.0	–	7.0	ns	1,7,8

Notes:
10. Minimum values are guaranteed but not tested on Propagation Delays.
11. These parameters are guaranteed but not tested.
*Refer to the 'Parameter Measurement Information' section of this book.

ORDERING INFORMATION